

Search Notes**Application/Control No.**

10/695,466

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under Reexamination

FONG ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
429	175	12/18/2006	DWY
429	181	12/18/2006	DWY
429	185	12/18/2006	DWY

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	12/18/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner